1

Ces, inc.

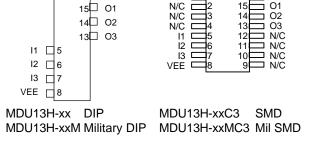
(R)

GND

TRIPLE, ECL-INTERFACED FIXED DELAY LINE (SERIES MDU13H)

FEATURES

- Three independent delay lines
- Fits standard 16-pin DIP socket
- Auto-insertable
- Input & outputs fully 10KH-ECL interfaced & buffered



GND

FUNCTIONAL DESCRIPTION

The MDU13H-series device is a 3-in-1 digitally buffered delay line. The signal inputs (I1-I3) are reproduced at the outputs (O1-O3), shifted in time by an amount determined by the device dash number (See Table). The delay lines function completely independently of each other.

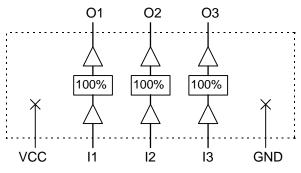
I1-I3 Signal Inputs

PIN DESCRIPTIONS

- O1-O3 Signal Outputs
- VEE -5 Volts
- GND Ground

SERIES SPECIFICATIONS

- Minimum input pulse width: 50% of total delay
- Output rise time: 2ns typical
- Supply voltage: $-5VDC \pm 5\%$
- Power dissipation: 200mw typical (no load)
- Operating temperature: -30° to 85° C
- Temp. coefficient of total delay: 100 PPM/°C



Functional block diagram

DASH NUMBER SPECIFICATIONS

Part Number	Delay Per Line (ns)
MDU13H-3	3 ± 1.0
MDU13H-4	4 ± 1.0
MDU13H-5	5 ± 1.0
MDU13H-10	10 ± 1.0
MDU13H-15	15 ± 1.0
MDU13H-20	20 ± 1.0
MDU13H-25	25 ± 2.0
MDU13H-30	30 ± 2.0
MDU13H-35	35 ± 2.0
MDU13H-40	40 ± 2.0
MDU13H-45	45 ± 2.2
MDU13H-50	50 ± 2.5

- * Total delay is referenced to first tap output Input to first tap = 1.5ns \pm 1ns
- NOTE: Any dash number between 3 and 50 not shown is also available.

©1997 Data Delay Devices

PACKAGES

GND 1 16 GND

data

APPLICATION NOTES

HIGH FREQUENCY RESPONSE

The MDU13H tolerances are guaranteed for input pulse widths and periods greater than those specified in the test conditions. Although the device will function properly for pulse widths as small as 50% of the total delay and periods as small as 100% of the total delay (for a symmetric input), the delays may deviate from their values at low frequency. However, for a given input condition, the deviation will be repeatable from pulse to pulse. Contact technical support at Data Delay Devices if your application requires device testing at a specific input condition.

POWER SUPPLY BYPASSING

The MDU13H relies on a stable power supply to produce repeatable delays within the stated tolerances. A 0.1uf capacitor from VEE to GND, located as close as possible to the VEE pin, is recommended. A wide VEE trace and a clean ground plane should be used.

DEVICE SPECIFICATIONS

PARAMETER	SYMBOL	MIN	MAX	UNITS	NOTES
DC Supply Voltage	V_{EE}	-7.0	0.3	V	
Input Pin Voltage	V _{IN}	V _{EE} - 0.3	0.3	V	
Storage Temperature	T _{STRG}	-55	150	С	
Lead Temperature	T _{LEAD}		300	С	10 sec

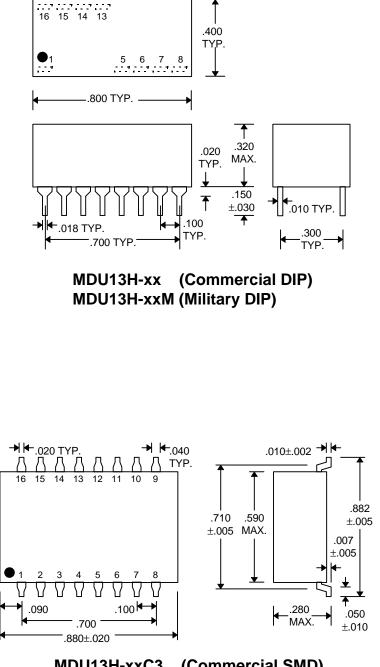
TABLE 1: ABSOLUTE MAXIMUM RATINGS

TABLE 2: DC ELECTRICAL CHARACTERISTICS (0C to 75C)

(0C to 75C)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	NOTES
High Level Output Voltage	V _{он}	-1.020		-0.735	V	$V_{IH} = MAX,50\Omega$ to -2V
Low Level Output Voltage	V _{OL}	-1.950		-1.600	V	$V_{IL} = MIN, 50\Omega$ to -2V
High Level Input Voltage	V _{IH}			-1.070	V	
Low Level Input Voltage	V _{IL}	-1.480			V	
High Level Input Current	I _{IH}			475	μA	$V_{IH} = MAX$
Low Level Input Current	IIL	0.5			μA	$V_{IL} = MIN$

PACKAGE DIMENSIONS



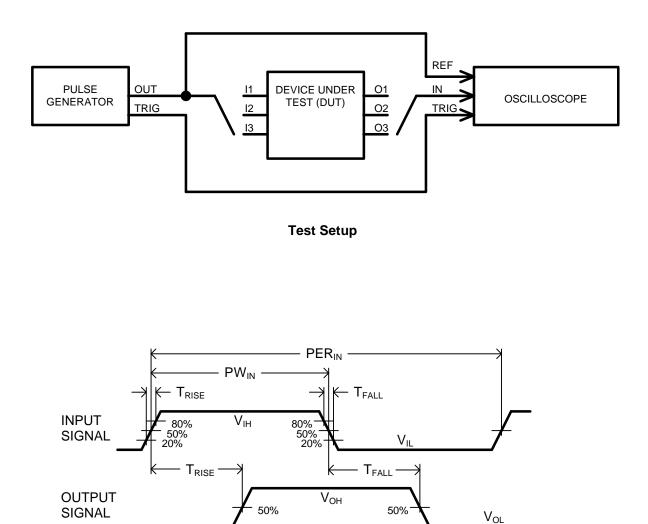
MDU13H-xxC3 (Commercial SMD) MDU13H-xxMC3 (Military SMD)

DELAY LINE AUTOMATED TESTING

TEST CONDITIONS

INPUT:		OUTPUT:	
Ambient Temperature:	$25^{\circ}C \pm 3^{\circ}C$	Load:	50Ω to -2V
Supply Voltage (Vcc):	$-5.0V \pm 0.1V$	C _{load} :	5pf ± 10%
Input Pulse:	Standard 10KH ECL	Threshold:	
	levels		(Rising & Falling)
Source Impedance:	50Ω Max.		
Rise/Fall Time:	2.0 ns Max. (measured		
	between 20% and 80%)		
Pulse Width:	PW _{IN} = 1.5 x Total Delay		
Period:	PER _{IN} = 10 x Total Delay		

NOTE: The above conditions are for test only and do not in any way restrict the operation of the device.



Timing Diagram For Testing